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4 M SRAM (512-kword  $\times$  8-bit)



ADE-203-935C (Z) Rev. 2.0 Aug. 24, 1999

### Description

The Hitachi HM628512BI is a 4-Mbit static RAM organized 512-kword  $\times$  8-bit. HM628512BI Series has realized higher density, higher performance and low power consumption by employing Hi-CMOS process technology. The HM628512BI Series offers low power standby power dissipation; therefore, it is suitable for battery backup systems. It has packaged in 32-pin SOP, 32-pin TSOP II and 32-pin DIP.

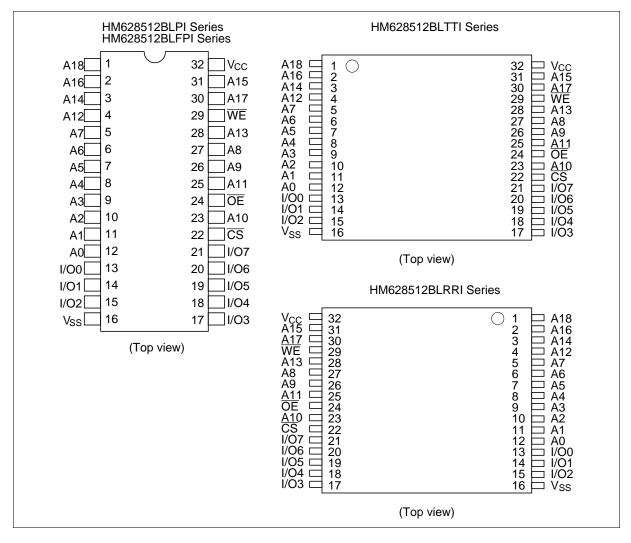
#### Features

- Single 5 V supply
- Access time: 70/85 ns (max)
- Power dissipation
  - Active: 50 mW/MHz (typ)
  - Standby: 10 µW (typ)
- Completely static memory. No clock or timing strobe required
- Equal access and cycle times
- Common data input and output: Three state output
- Directly TTL compatible: All inputs and outputs
- Battery backup operation
- Operating temperature: -40 to +85°C

## **Ordering Information**

Type No.	Access time	Package
HM628512BLPI-7 HM628512BLPI-8	70 ns 85 ns	600-mil 32-pin plastic DIP (DP-32)
HM628512BLFPI-7 HM628512BLFPI-8	70 ns 85 ns	525-mil 32-pin plastic SOP (FP-32D)
HM628512BLTTI-7 HM628512BLTTI-8	70 ns 85 ns	400-mil 32-pin plastic TSOP II (TTP-32D)
HM628512BLRRI-7 HM628512BLRRI-8	70 ns 85 ns	400-mil 32-pin plastic TSOP II reverse (TTP-32DR)

#### **Pin Arrangement**

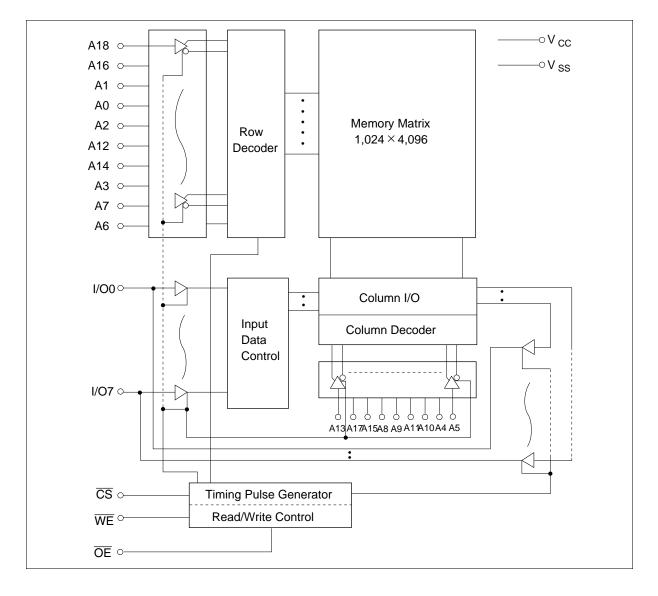


## **Pin Description**

Pin name	Function		
A0 to A18	Address input		
I/O0 to I/O7	Data input/output		
CS	Chip select		
ŌĒ	Output enable		
WE	Write enable		
V <sub>cc</sub>	Power supply		
V <sub>ss</sub>	Ground		



#### **Block Diagram**



#### **Function Table**

WE	CS	ŌE	Mode	V <sub>cc</sub> current	Dout pin	Ref. cycle
×	Н	×	Not selected	$I_{SB},I_{SB1}$	High-Z	_
Н	L	Н	Output disable	I <sub>cc</sub>	High-Z	_
Н	L	L	Read	I <sub>cc</sub>	Dout	Read cycle
L	L	Н	Write	I <sub>cc</sub>	Din	Write cycle (1)
L	L	L	Write	I <sub>cc</sub>	Din	Write cycle (2)

Note: X: H or L

## **Absolute Maximum Ratings**

Parameter	Symbol	Value	Unit
Power supply voltage	V <sub>cc</sub>	–0.5 to +7.0	V
Voltage on any pin relative to $\rm V_{ss}$	V <sub>T</sub>	$-0.5^{*1}$ to V <sub>cc</sub> + 0.3 <sup>*2</sup>	V
Power dissipation	P <sub>T</sub>	1.0	W
Operating temperature	Topr	-40 to +85	°C
Storage temperature	Tstg	–55 to +125	°C
Storage temperature under bias	Tbias	-40 to +85	°C

Notes: 1. -3.0 V for pulse half-width  $\leq 30$  ns

2. Maximum voltage is 7.0 V

## **Recommended DC Operating Conditions** (Ta = -40 to $+85^{\circ}$ C)

Parameter	Symbol	Min	Тур	Max	Unit
Supply voltage	V <sub>cc</sub>	4.5	5.0	5.5	V
	V <sub>ss</sub>	0	0	0	V
Input high voltage	V <sub>IH</sub>	2.4	—	V <sub>cc</sub> + 0.3	V
Input low voltage	V <sub>IL</sub>	-0.3*1		0.6	V

Note: 1. -3.0 V for pulse half-width  $\leq 30$  ns

## **DC Characteristics** (Ta = -40 to $+85^{\circ}$ C, $V_{CC} = 5$ V $\pm 10\%$ , $V_{SS} = 0$ V)

Parameter	Symbol	Min	Typ* <sup>1</sup>	Max	Unit	Test conditions
Input leakage current	I <sub>LI</sub>		_	1	μΑ	$Vin = V_{ss} to V_{cc}$
Output leakage current	<sub>lo</sub>			1	μA	$\overline{\frac{CS}{WE}} = V_{IH} \text{ or } \overline{OE} = V_{IH} \text{ or } $ $\overline{WE} = V_{IL}, V_{I/O} = V_{SS} \text{ to } V_{CC}$
Operating power supply current: DC	I <sub>cc</sub>	—	8	15	mA	$\overline{CS} = V_{IL},$ others = $V_{IH}/V_{IL}$ , $I_{I/O} = 0$ mA
Operating power supply current	I <sub>cc1</sub>	_	45	70	mA	$\label{eq:constraint} \begin{array}{l} \mbox{Min cycle, duty} = 100\% \\ \hline \mbox{CS} = \mbox{V}_{\mbox{\tiny IL}}, \mbox{ others} = \mbox{V}_{\mbox{\tiny IH}} / \mbox{V}_{\mbox{\tiny IL}} \\ \hline \mbox{I}_{\mbox{\tiny IO}} = 0 \mbox{ mA} \end{array}$
Operating power supply current	I <sub>CC2</sub>	_	10	20	mA	$ \begin{array}{l} Cycle \ time = 1 \ \mu s, \\ duty = 100\% \\ I_{_{VO}} = 0 \ mA, \ \overline{CS} \leq 0.2 \ V \\ V_{_{IH}} \geq V_{_{CC}} - 0.2 \ V, \ V_{_{IL}} \leq 0.2 \ V \end{array} $
Standby power supply current: DC	I <sub>SB</sub>	_	1	3	mA	$\overline{\text{CS}} = \text{V}_{\text{IH}}$
Standby power supply current (1): DC	I <sub>SB1</sub>		2	100	μΑ	Vin $\geq$ 0 V, $\overline{\text{CS}} \geq$ V $_{\text{cc}}$ – 0.2 V
Output low voltage	V <sub>OL</sub>	_	_	0.4	V	I <sub>oL</sub> = 2.1 mA
Output high voltage	V <sub>OH</sub>	2.4	_	_	V	I <sub>OH</sub> = -1.0 mA

Note: 1. Typical values are at  $V_{cc}$  = 5.0 V, Ta = +25°C and specified loading, and not guaranteed.

## **Capacitance** (Ta = $+25^{\circ}$ C, f = 1 MHz)

Parameter	Symbol	Тур	Max	Unit	Test conditions
Input capacitance*1	Cin	_	8	pF	Vin = 0 V
Input/output capacitance*1	C <sub>I/O</sub>		10	pF	$V_{I/O} = 0 V$

Note: 1. This parameter is sampled and not 100% tested.

## AC Characteristics (Ta = -40 to $+85^{\circ}$ C, V<sub>CC</sub> = 5 V ± 10%, unless otherwise noted.)

#### **Test Conditions**

- Input pulse levels: 0.5 V to 2.5 V
- Input rise and fall time: 5 ns
- Input and output timing reference levels: 1.5 V
- Output load: 1 TTL Gate +  $C_L$  (100 pF) (Including scope and jig)

#### **Read Cycle**

		HM628512BI					
		-7		-8			
Parameter	Symbol	Min	Max	Min	Max	Unit	Notes
Read cycle time	t <sub>RC</sub>	70	_	85	_	ns	
Address access time	t <sub>AA</sub>	—	70		85	ns	
Chip select access time	t <sub>co</sub>	—	70		85	ns	
Output enable to output valid	t <sub>oe</sub>	—	35		45	ns	
Chip selection to output in low-Z	t <sub>LZ</sub>	10		10		ns	2
Output enable to output in low-Z	t <sub>oLZ</sub>	5		5		ns	2
Chip deselection to output in high-Z	t <sub>HZ</sub>	0	25	0	30	ns	1, 2
Output disable to output in high-Z	t <sub>oHZ</sub>	0	25	0	30	ns	1, 2
Output hold from address change	t <sub>on</sub>	10	_	10	—	ns	



#### Write Cycle

		HM62	8512BI				
		-7		-8			
Parameter	Symbol	Min	Max	Min	Max	Unit	Notes
Write cycle time	t <sub>wc</sub>	70		85	—	ns	
Chip selection to end of write	t <sub>cw</sub>	60		75		ns	4
Address setup time	t <sub>AS</sub>	0	_	0	_	ns	5
Address valid to end of write	t <sub>AW</sub>	60	_	75	_	ns	
Write pulse width	t <sub>wP</sub>	50	_	55	_	ns	3, 12
Write recovery time	t <sub>wR</sub>	0	_	0	_	ns	6
WE to output in high-Z	t <sub>wHZ</sub>	0	25	0	30	ns	1, 2, 7
Data to write time overlap	t <sub>DW</sub>	30	_	35	_	ns	
Data hold from write time	t <sub>DH</sub>	0	_	0	_	ns	
Output active from output in high-Z	t <sub>ow</sub>	5	_	5	_	ns	2
Output disable to output in high-Z	t <sub>oHz</sub>	0	25	0	30	ns	1, 2, 7

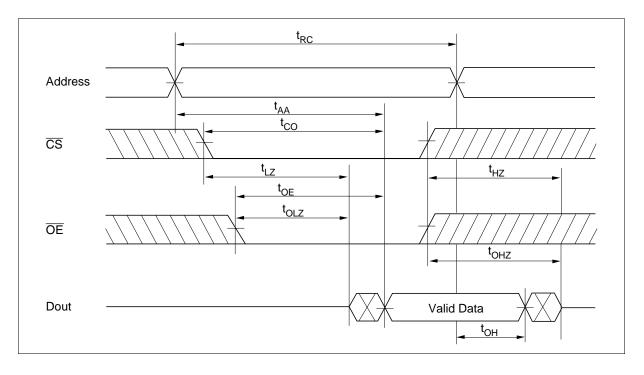
Notes: 1. t<sub>HZ</sub>, t<sub>OHZ</sub> and t<sub>WHZ</sub> are defined as the time at which the outputs achieve the open circuit conditions and are not referred to output voltage levels.

- 2. This parameter is sampled and not 100% tested.
- 3. A write occurs during the overlap (t<sub>WP</sub>) of a low CS and a low WE. A write begins at the later transition of CS going low or WE going low. A write ends at the earlier transition of CS going high or WE going high. t<sub>WP</sub> is measured from the beginning of write to the end of write.
- 4.  $t_{cw}$  is measured from  $\overline{CS}$  going low to the end of write.
- 5.  $t_{AS}$  is measured from the address valid to the beginning of write.
- 6.  $t_{WR}$  is measured from the earlier of  $\overline{WE}$  or  $\overline{CS}$  going high to the end of write cycle.
- 7. During this period, I/O pins are in the output state so that the input signals of the opposite phase to the outputs must not be applied.
- 8. If the CS low transition occurs simultaneously with the WE low transition or after the WE transition, the output remain in a high impedance state.
- 9. Dout is the same phase of the write data of this write cycle.
- 10. Dout is the read data of next address.
- 11. If  $\overline{CS}$  is low during this period, I/O pins are in the output state. Therefore, the input signals of the opposite phase to the outputs must not be applied to them.
- 12. In the write cycle with  $\overline{OE}$  low fixed,  $t_{WP}$  must satisfy the following equation to avoid a problem of data bus contention.  $t_{WP} \ge t_{DW}$  min +  $t_{WHZ}$  max



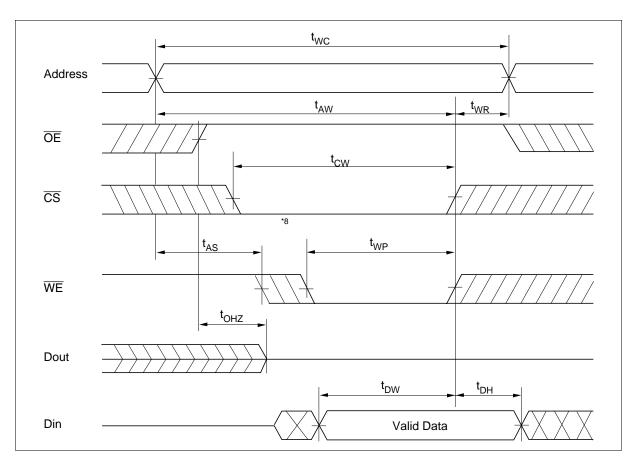
## **Timing Waveforms**

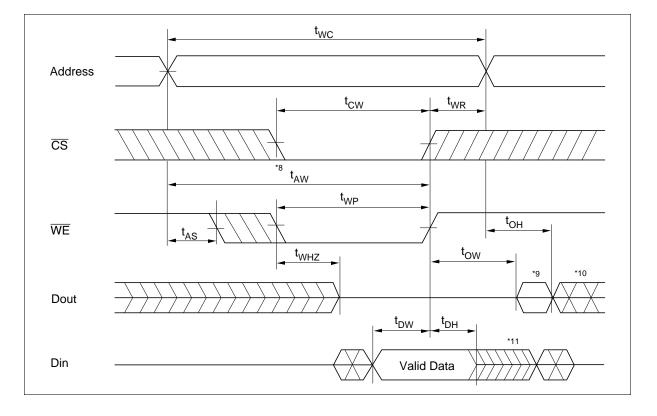
## Read Timing Waveform $(\overline{WE}=V_{\rm IH})$





## Write Timing Waveform (1) $(\overline{OE} Clock)$





Write Timing Waveform (2) (OE Low Fixed)

#### Low $V_{cc}$ Data Retention Characteristics (Ta = -40 to +85°C)

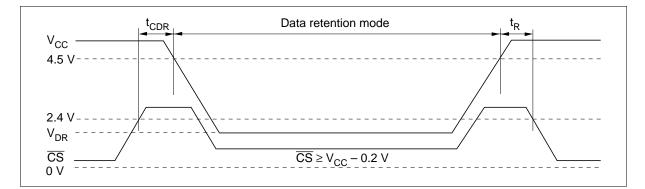
Parameter	Symbol	Min	Тур	Max	Unit	Test conditions*2
$V_{cc}$ for data retention	$V_{\text{DR}}$	2	_	_	V	$\overline{\text{CS}} \ge \text{V}_{\text{cc}} - 0.2 \text{ V}, \text{ Vin} \ge 0 \text{ V}$
Data retention current	I <sub>CCDR</sub>		1* <sup>3</sup>	50* <sup>1</sup>	μΑ	$\frac{V_{cc}}{CS} = 3.0 \text{ V}, \text{ Vin} \ge 0 \text{ V}$ $\frac{V_{cc}}{CS} \ge V_{cc} - 0.2 \text{ V}$
Chip deselect to data retention time	$t_{CDR}$	0		—	ns	See retention waveform
Operation recovery time	t <sub>R</sub>	$t_{RC}^{*4}$	—		ns	_

Notes: 1. For L-version and 20  $\mu$ A (max.) at Ta = -40 to +40°C.

2. CS controls address buffer, WE buffer, OE buffer, and Din buffer. In data retention mode, Vin levels (address, WE, OE, I/O) can be in the high impedance state.

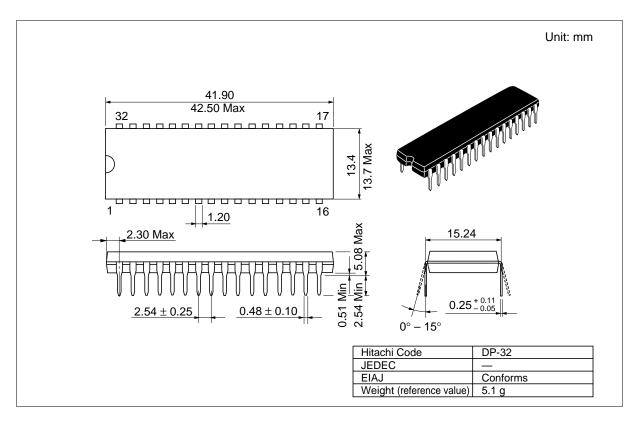
- 3. Typical values are at  $V_{cc}$  = 3.0 V, Ta = +25°C and specified loading, and not guaranteed.
- 4.  $t_{RC}$  = read cycle time.

#### Low $V_{CC}$ Data Retention Timing Waveform ( $\overline{CS}$ Controlled)



### **Package Dimensions**

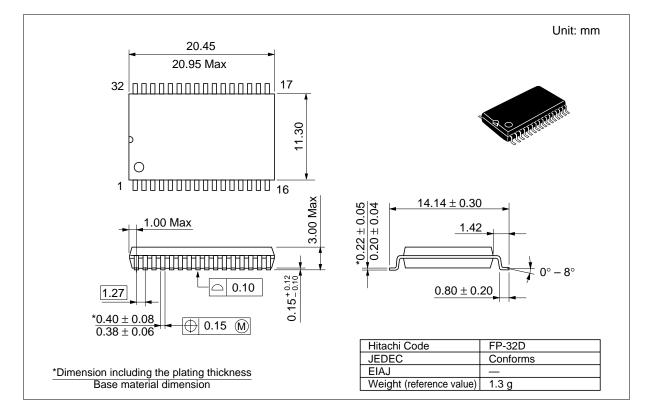
#### HM628512BLPI Series (DP-32)





#### Package Dimensions (cont.)

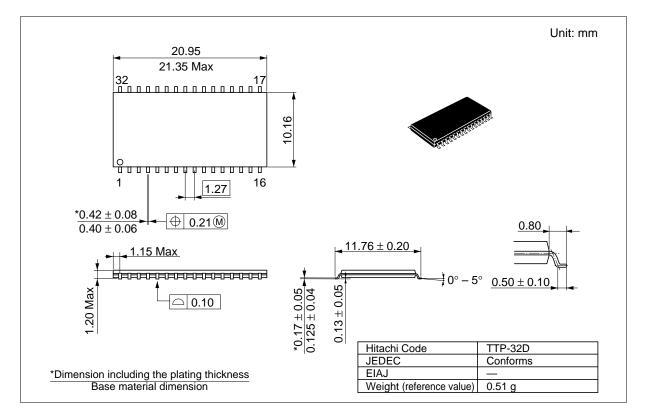
#### HM628512BLFPI Series (FP-32D)





#### Package Dimensions (cont.)

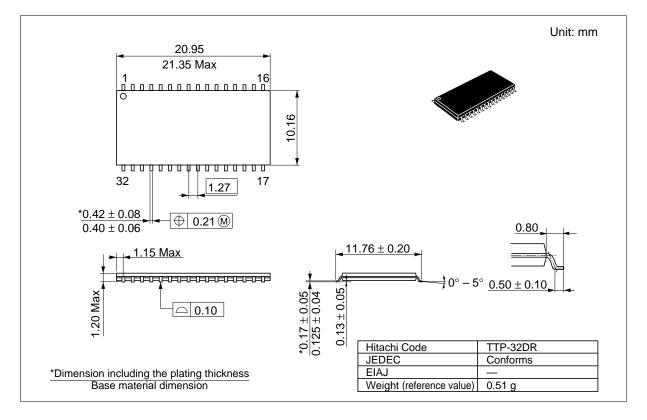
#### HM628512BLTTI Series (TTP-32D)





#### Package Dimensions (cont.)

#### HM628512BLRRI Series (TTP-32DR)





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